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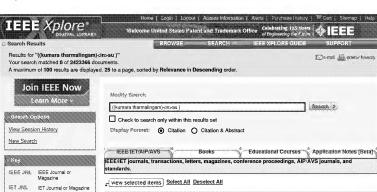Help   Contact Us   Privacy & Security   IEEE.org

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